

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re U.S. Patent Application of:

BIERMANN
Serial No.: To Be Assigned }
Filed: Concurrently Herewith }
For: METHOD FOR DETERMINING THE }
EFFECTS OF FANCY YARN }

Charlotte, North Carolina, April 11, 2006

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the Applicant's duty of disclosure under 37 CFR 1.56, the applicant submits this Information Disclosure Statement pursuant to the provisions of 37 CFR 1.97. A PTO Form 1449 listing references known to the applicants is attached. Copies of the German patent and the Patent Abstracts of Japan are enclosed, and the U.S. Patents are listed on the attached PTO-1449.

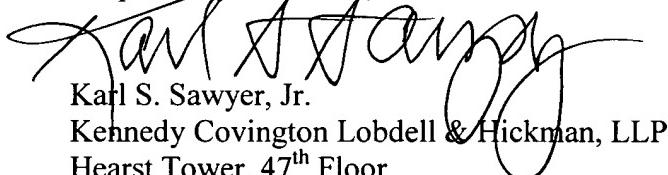
The applicant does not have an English translation of the remaining reference submitted herewith, which is discussed below. The Examiner is encouraged to undertake his or her own detailed evaluation of this reference. As to this reference for which no English abstract or counterpart exists, the applicant believes that the following is a reasonable and accurate summary of the substance of the reference.

DE 100 26 389 A1 describes a device for monitoring a running yarn by means of a sensor device of a spinning unit. If the value of the diameter exceeds selected tolerance limits over a predetermined length, it is concluded that this is the start of a defect location. If thereafter the value of the diameter again extends for a sufficient length of time within the tolerance zone, it is concluded that this is the end of the defect location. Here, every one of the tolerance deviations is categorized as a yarn defect. The diameter values detected following each other in the running yarn are detected as the progression of a curve over the length of the yarn, and the curve is stored in a data memory. The data memory contains predetermined patterns of the run of the curve,

which represent a section of the progression of the curve in the area of a defect location, as pattern types. Because of the form of the progression of their curves, the pattern types permit the drawing of conclusions regarding the reasons for the defect. To determine whether a predetermined pattern type is repeated in the progression of the curve, the progression of the curve is compared with the predetermined pattern types. If in the course of this it is determined that a defect location corresponds to a pattern type, the type of the defect and the reason for the effect are determined by means of the detected pattern type and their repair is triggered. Although it is possible by means of the device of DE 100 26 389 A1 to improve the detection and quality of statements regarding the defect and the reason for the defect, it is not always possible to a sufficient extent to monitor the running yarn as to whether the diameters of ornamentations are designed as desired.

No admission is made that the information cited in this Statement is, or is considered to be, material to patentability nor a representation that a search has been made (other than search report(s) from a counterpart foreign application or a PCT International Search Report, if submitted herewith). 37 CFR §§ 1.97(g) and (h).

Respectfully submitted,


Karl S. Sawyer, Jr.
Kennedy Covington Lobdell & Hickman, LLP
Hearst Tower, 47th Floor
214 North Tryon Street
Charlotte, North Carolina 28202
Telephone (704) 331-7400
-- Attorney for Applicant

Attorney Docket No.: 2209.943(WS2241.1US-PCT)

0243147.01
LIB:

10/15/5566
Serial No.
To Be Assigned

Form PTO-1449 (Rev. 7-80)		U.S. Department of Commerce Patent and Trademark Office			Atty. Docket No. 2209.943(WS2241.1US-PCT)		
					Applicant BIERMANN		
LIST OF REFERENCES CITED BY APPLICANT (Use Several Sheets if Necessary)					Filing Date Concurrently Herewith	Group To Be Assigned	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document No.	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	3,303,698	02/14/1967	Loepfe	73	160	Dec. 16, 1963
	AB	5,119,308	06/02/1992	Samoto	364	470	Aug. 21, 1989
	AC						
	AD						
	AE						
	AF						
FOREIGN PATENT DOCUMENTS							
		Document No.	Date	Country	Class	Subclass	Translation Yes No
	AG	DE 100 26 389 A1	3/22/2001	Germany			X
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AN	Patent Abstracts of Japan – JP 02-221427, 4 September 1990					
	AO	Patent Abstracts of Japan – JP 06-128821, 10 May 1994					
Examiner				Date Considered			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication with applicant.							